

## **DT – 630 SERIES**

**The Art Of Test Solutions**

**Multi Channel Stackable IC Test System**

**Individual on-board Microprocessor for accurate and fast processing**

**512 Channel Multi Voltage-Current Sourcing Dual independent High Precision Source and Measurement unit**

**High flexibility via Multi-layer MUX connection for each channel**



**Option of up to 512 independent channels for increased IC testing flexibility.**

**Flexible system configuration is achieved by stacking, to provide up to 5K test channels.**

**2 independent high precision multi-range Source and Measurement units.**

**True 4 quadrant sourcing capability for each channel, using 4-wire test methodology.**

**Multiple current and voltage range to increase accuracy and sensitivity.**

**High precision measurement capability can be achieved using true 4-wire test methodology for each channel.**

**True High Precision 24-Bit ADC Sense Circuits.**

**Shielded noise suppression power supply to ensure low current accuracy.**

**Standalone or networked configuration.**

**Custom software interface with TCP/IP capability for direct data transfer and remote monitoring.**

**Compact casing design with Industrial Double Shielding Design.**

**Easy maintenance via Interchangeable Front Slot Removable Modular Units.**

**Interface options RS-232, RS-485, USB, Digital Opto-Isolated IO, TTL.**

# DT – 630 SERIES Specifications

## TECHNICAL SPECIFICATION

VOLTAGE SENSE RESOLUTION	VOLTAGE STEP RESOLUTION	ACCURACY	REMARKS
+ - 15V	895 nV	0.5%	- H Option
+ - 10V	596 nV	0.5%	Standard
+ - 5V	298 nV	0.5%	Standard
+ - 2.5V	149 nV	0.5%	Standard
+ - 1.25V	75 nV	0.5%	Standard

CURRENT SENSE RESOLUTION	CURRENT STEP RESOLUTION	ACCURACY	REMARKS
250 mA	15 nA	0.5%	Standard
25 mA	1.5 nA	0.5%	Standard
2.5 mA	150 pA	0.5%	Standard
0. 25 mA	15 pA	0.5%	Standard
0. 025 mA	1.5 pA	1.0%	Standard



**TESTLOGICS**<sup>TM</sup>  
THE ART OF TEST SOLUTIONS